

## **ARFTG Workshop: High frequency and high bandwidth measurements for 5G and related applications**

Wednesday, January 23, 2019 1300-1700

Rosen Plaza Hotel

As carrier frequencies and instantaneous bandwidths increase to support 5G communication and other applications, measurement (and design) challenges increase as well. This workshop will delve into some of these interesting and critical areas: mm-wave on-wafer measurement complications (including effects of nearby structures and multimode propagation), nano device characterization and materials measurement issues, waveform measurements and energy efficiency challenges in mm-wave power amplifiers, and mm-wave/broadband load pull. These measurement issues affect many aspects of mm-wave and broadband circuit and system development and the speakers will be covering a wide-ranging set of important topics.

Speakers:

Challenges review and Testing Options to help Success in the Implementation of 5G-NR Systems - Earl McCune (Eridan Communications)

Uncertainties in mm-wave on-wafer measurements - Uwe Arz (PTB)

Measurement solutions for circuits at microwave and millimeter-wave frequency - Masahiro Horibe (AIST)

Calibration and large-signal challenges and solutions for mm-wave and sub-mm-wave VNA based setups - Luca Galatro (Vertigo technologies)

Wideband load-pull measurement techniques: architecture, accuracy, and applications - Mauro Marchetti and Gustavo Avolio (Anteverta-MW)